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(IEC 62271-101:2021)**

High-voltage switchgear and controlgear - Part 101: Synthetic testing (IEC 62271-101:2021)

Hochspannungs-Schaltgeräte und -Schaltanlagen - Teil 101: Synthetische Prüfung (IEC 62271-101:2021)

Appareillage à haute tension - Partie 101: Essais synthétiques (IEC 62271-101:2021)

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(IEC 62271-101:2021)

Hochspannungs-Schaltgeräte und -Schaltanlagen - Teil
101: Synthetische Prüfung
(IEC 62271-101:2021)

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EN IEC 62271-101:2021 (E)**European foreword**

The text of document 17A/1312/FDIS, future edition 3 of IEC 62271-101, prepared by SC 17A “Switching devices” of IEC/TC 17 “High-voltage switchgear and controlgear” was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62271-101:2021.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2022-05-31 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2024-08-31 document have to be withdrawn

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

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High-voltage switchgear and controlgear –
Part 101: Synthetic testing

Appareillage à haute tension –
Partie 101: Essais synthétiques

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CONTENTS

FOREWORD.....	9
1 Scope.....	11
2 Normative references.....	11
3 Terms and definitions	11
4 Synthetic testing techniques and methods for short-circuit breaking tests.....	13
4.1 Basic principles and general requirements for synthetic breaking test methods.....	13
4.1.1 General	13
4.1.2 High-current interval.....	14
4.1.3 Interaction interval	15
4.1.4 High-voltage interval	15
4.2 Synthetic test circuits and related specific requirements for breaking tests	18
4.2.1 Current injection methods.....	18
4.2.2 Voltage injection method	19
4.2.3 Duplicate circuit method (transformer or Skeats circuit).....	20
4.2.4 Other synthetic test methods	20
4.3 Three-phase synthetic test methods	20
5 Synthetic testing techniques and methods for short-circuit making tests.....	24
5.1 Basic principles and general requirements for synthetic making test methods	24
5.1.1 General	24
5.1.2 High-voltage interval	27
5.1.3 Pre-arcing interval.....	27
5.1.4 Latching interval and fully closed position	27
5.2 Synthetic test circuit and related specific requirements for making tests	27
5.2.1 General	27
5.2.2 Test circuit and test requirements.....	27
5.2.3 Alternative test method with reduced voltage	32
7 Type tests	33
7.102 General.....	33
7.104 Demonstration of arcing times	34
7.107 Terminal fault tests.....	45
7.109 Short-line fault tests	49
7.110 Out-of-phase making and breaking tests	50
7.111 Capacitive current tests.....	50
Annex A (normative) Correction of di/dt and TRV for test duty T100a	53
A.1 General.....	53
A.2 Reduction in di/dt	53
A.3 Corrected TRV for the first-pole-to-clear with required asymmetry	53
A.4 Correction of the di/dt and TRV of the first-pole-to-clear for tests with intermediate asymmetry	60
A.5 Correction of the di/dt and TRV of the second- or last-pole-to-clear with major extended loop with required asymmetry during three-phase tests.....	61
A.6 Correction of the di/dt and TRV during tests with a subsequent minor loop	61
A.7 Calculation of the di/dt and TRV of the first-pole-to-clear	61
A.7.1 General	61
A.7.2 Calculation of di/dt	61

A.7.3	Calculation of TRV	62
A.7.4	Examples of calculation of di/dt and TRV.....	64
Annex B (normative)	Tolerances on test quantities for type tests.....	66
Annex C (normative)	Information to be given and results to be recorded for synthetic tests	69
C.1	General.....	69
C.2	Auxiliary circuit-breaker	69
C.3	Test conditions.....	69
C.4	Quantities to be recorded	69
C.4.1	General	69
C.4.2	Voltages	69
C.4.3	Currents	69
Annex D (normative)	Test procedure using a three-phase current circuit and one voltage circuit	70
D.1	Test circuit	70
D.2	Test method	71
D.2.1	General	71
D.2.2	Test duty T100s(b).....	71
D.2.3	Test duty T100a	80
D.2.4	Combination of first-pole-to-clear factors 1,3 and 1,5	89
Annex E (normative)	Splitting of test duties in test series taking into account the associated TRV for each pole-to-clear.....	92
E.1	General.....	92
E.2	Test-duties T10, T30, T60, T100s(b), OP1 and OP2(b).....	92
E.2.1	Test procedure for first-pole-to-clear factors 1,5 and 2,5	92
E.2.2	Test procedure for first-pole-to-clear factors 1,3 and 2,0	93
E.2.3	Test procedure for first-pole-to-clear factor 1,2	94
E.3	Test duty T100a	95
E.3.1	General	95
E.3.2	Test procedure for first-pole-to-clear factor 1,5	96
E.3.3	Test procedure for first-pole-to-clear factor 1,3	97
E.3.4	Test procedure for first-pole-to-clear factor 1,2	99
E.4	Combination of first-pole-to-clear factors	100
E.4.1	General	100
E.4.2	Combination of first-pole-to-clear factors 1,3 and 1,5 for test duties T10, T30, T60 and T100s(b).....	100
E.4.3	Combination of first-pole-to-clear factors 2,0 and 2,5 for test duties OP1 and OP2(b).....	101
E.4.4	Combination of first-pole-to-clear factors 1,3 and 1,5 for test duty T100a.....	102
Annex F (informative)	Three-phase synthetic test circuits	114
F.1	General.....	114
F.2	Three-phase synthetic combined circuit	114
F.3	Three-phase synthetic circuit with injection in all phases	117
F.4	Three-phase synthetic circuit with injection in two phases	118
Annex G (informative)	Examples of test circuits for metal-enclosed and dead tank circuit-breakers.....	122
Annex H (informative)	Step-by-step method to prolong arcing	133
Annex I (informative)	Synthetic methods for capacitive current tests	135
I.1	General.....	135

I.2	Recovery voltage	135
I.3	Combined current and voltage circuits	135
I.4	Making tests	136
I.5	Current chopping	136
I.6	Examples test circuits	136
Annex J (normative)	Synthetic test methods for circuit-breakers with opening resistors	145
J.1	General.....	145
J.2	Conditions.....	145
J.2.1	General	145
J.2.2	Transient recovery voltage interval	145
J.2.3	Power-frequency recovery voltage interval.....	145
J.3	Multiple step test procedure	145
J.3.1	General	145
J.3.2	Test to verify the re-ignition behaviour of the making and breaking unit	146
J.3.3	Test to verify the re-ignition behaviour of the making and breaking unit during short circuit test duties with any test method	147
J.3.4	Tests on resistor switch(s).....	148
J.4	Test requirements	149
J.4.1	General	149
J.4.2	Testing of the making and breaking unit.....	150
J.4.3	Testing of the resistor switch.....	151
J.4.4	Test of the resistor stack	151
Annex K (informative)	Combination of current injection and voltage injection methods.....	152
K.1	Current injection methods.....	152
K.2	Voltage injection methods	152
K.3	Combined current and voltage injection circuits.....	152
K.3.1	General	152
K.3.2	Combined current and voltage injection circuit with application of full test voltage to earth	152
K.3.3	Combined current and voltage injection circuit with separated application of test voltage.....	152
Bibliography	155
Figure 1	– Interrupting process – Basic time intervals	14
Figure 2	– Examples of evaluation of initial recovery voltage.....	17
Figure 3	– Equivalent surge impedance of the voltage circuit for the current injection method.....	19
Figure 4	– Reference lines of TRV with four-parameter for $k_{pp} = 1,5$	22
Figure 5	– Reference lines of TRV with four-parameter for $k_{pp} = 1,3$	23
Figure 6	– Reference lines of TRV with four-parameter for $k_{pp} = 1,2$	24
Figure 7	– Making process – Basic time intervals.....	26
Figure 8	– Example of synthetic making circuit for single-phase tests.....	29
Figure 9	– Example of synthetic making circuit for out-of-phase tests	30
Figure 10	– Example of synthetic making circuit for three-phase tests ($k_{pp} = 1,5$).....	31
Figure 11	– Comparison of arcing time settings during three-phase direct tests (left) and three-phase synthetic (right) for T100s with $k_{pp} = 1,5$	37

Figure 12 – Comparison of arcing time settings during three-phase direct tests (left) and three-phase synthetic (right) for T100s with $k_{pp} = 1,3$	38
Figure 13 – Comparison of arcing time settings during three-phase direct tests (left) and three-phase synthetic tests (right) for T100a with $k_{pp} = 1,5$	41
Figure 14 – Comparison of arcing time settings during three-phase direct tests (left) and three-phase synthetic tests (right) for T100a with $k_{pp} = 1,3$	42
Figure 15 – Evaluation of recovery voltage during synthetic capacitive current switching testing	52
Figure D.1 – Example of a three-phase current circuit with single-phase synthetic injection	71
Figure D.2 – Representation of the testing conditions of Table D.1	73
Figure D.3 – Representation of the testing conditions of Table D.2	75
Figure D.4 – Representation of the testing conditions of Table D.3	77
Figure D.5 – Representation of the testing conditions of Table D.4	79
Figure D.6 – Representation of the testing conditions of Table D.5	82
Figure D.7 – Representation of the testing conditions of Table D.6	84
Figure D.8 – Representation of the testing conditions of Table D.7	86
Figure D.9 – Representation of the testing conditions of Table D.8	88
Figure E.1 – Example of graphical representation of the tests shown in Table E.6	97
Figure E.2 – Example of graphical representation of the tests shown in Table E.7 and Table E.8	99
Figure F.1 – Three-phase synthetic combined circuit	115
Figure F.2 – Waveshapes of currents, phase-to-ground and phase-to phase voltages during a three-phase synthetic test (T100s; $k_{pp} = 1,5$) performed according to the three-phase synthetic combined circuit	116
Figure F.3 – Three-phase synthetic circuit with injection in all phases for $k_{pp} = 1,5$	117
Figure F.4 – Waveshapes of currents and phase-to-ground voltages during a three-phase synthetic test (T100s; $k_{pp} = 1,5$) performed according to the three-phase synthetic circuit with injection in all phases	118
Figure F.5 – Three-phase synthetic circuit for terminal fault tests with $k_{pp} = 1,3$ (current injection method)	119
Figure F.6 – Waveshapes of currents and phase-to-ground voltages during a three-phase synthetic test (T100s; $k_{pp} = 1,3$) performed according to the three-phase synthetic circuit shown in Figure F.5	120
Figure F.7 – TRV voltages waveshapes of the test circuit described in Figure F.5	121
Figure G.1 – Example of a test circuit for unit testing (circuit-breaker with interaction due to gas circulation)	123
Figure G.2 – Oscillogram corresponding to Figure G.1 – Example of the required TRVs to be applied between the terminals of the unit(s) under test and between the live parts and the insulated enclosure	124
Figure G.3 – Example of test circuit using two voltage circuits for breaking tests	125
Figure G.4 – Example of test circuit using two voltage circuits for breaking tests	126
Figure G.5 – Example of a synthetic test circuit for unit testing (if unit testing is allowed as per 7.102.4.2 of IEC 62271-100:2021)	127
Figure G.6 – Oscillogram corresponding to Figure G.3 – Example of the required TRVs to be applied between the terminals of the unit(s) under test and between the live parts and the insulated enclosure	128

Figure G.7 – Example of a capacitive current injection circuit with enclosure of the circuit-breaker energized	129
Figure G.8 – Example of a capacitive synthetic circuit using two power-frequency circuits and with the enclosure of the circuit-breaker energized	130
Figure G.9 – Example of a capacitive synthetic current injection circuit – Unit testing on half a pole of a circuit-breaker with two units per pole – Enclosure energized with DC voltage	131
Figure G.10 – Example of a synthetic making circuit for out-of-phase tests	132
Figure H.1 – Example of a re-ignition circuit diagram for prolonging arc-duration	133
Figure H.2 – Example of waveforms obtained during a symmetrical test using the circuit in Figure H.1	134
Figure I.1 – Power-frequency circuits in parallel	138
Figure I.2 – Current injection circuit	139
Figure I.3 – Power-frequency current injection circuit	140
Figure I.4 – Current injection circuit, recovery voltage applied to both terminals of the circuit-breaker	141
Figure I.5 – Current injection circuit with decay compensation	142
Figure I.6 – LC oscillating circuit	143
Figure I.7 – Inrush making current test circuit	144
Figure J.1 – Test circuit to verify re-ignition behaviour of the making and breaking unit using current injection method	147
Figure J.2 – Test circuit to verify re-ignition behaviour of the making and breaking unit	148
Figure J.3 – Test circuit on the resistor switch	149
Figure J.4 – Example of test circuit for capacitive current switching tests on the making and breaking unit	150
Figure J.5 – Example of test circuit for capacitive current switching tests on the resistor switch	151
Figure K.1 – Example of combined current and voltage injection circuit with application of full test voltage to earth	153
Figure K.2 – Example of combined current and voltage injection circuit with separated application of test voltage	154
Table 1 – Tolerances and limits required during the high-current interval	15
Table 2 – Test circuits for test duties T100s and T100a	21
Table 3 – Test parameters during three-phase interruption for test-duties T10, T30, T60 and T100s, $k_{pp} = 1,5$	21
Table 4 – Test parameters during three-phase interruption for test-duties T10, T30, T60 and T100s, $k_{pp} = 1,3$	22
Table 5 – Test parameters during three phase interruption for test-duties T10, T30, T60 and T100s, $k_{pp} = 1,2$	23
Table 6 – Symbols and abbreviated terms used for operation during synthetic tests	33
Table 7 – Synthetic test methods for test duties T10, T30, T60, T100s, T100a, SP, DEF, OP and SLF	46
Table A.1 – Corrected TRV values for the first-pole-to-clear for $k_{pp} = 1,3$ and $f_r = 50$ Hz	54
Table A.2 – Corrected TRV values for the first-pole-to-clear for $k_{pp} = 1,3$ and $f_r = 60$ Hz	55

Table A.3 – Corrected TRV values for the first-pole-to-clear for $k_{pp} = 1,5$ and $f_r = 50$ Hz	57
Table A.4 – Corrected TRV values for the first-pole-to-clear for $k_{pp} = 1,5$ and $f_r = 60$ Hz	58
Table A.5 – Corrected TRV values for the first-pole-to-clear for $k_{pp} = 1,2$ and $f_r = 50$ Hz	58
Table A.6 – Corrected TRV values for the first-pole-to-clear for $k_{pp} = 1,2$ and $f_r = 60$ Hz	59
Table A.7 – Percentage of DC component and di/dt at current zero for first-pole-to-clear for $f_r = 50$ Hz	59
Table A.8 – Percentage of DC component and di/dt at current zero for first-pole-to-clear for $f_r = 60$ Hz	60
Table B.1 – Tolerances on test quantities for type tests	67
Table D.1 – Demonstration of arcing times for $k_{pp} = 1,5$	72
Table D.2 – Alternative demonstration of arcing times for $k_{pp} = 1,5$	74
Table D.3 – Demonstration of arcing times for $k_{pp} = 1,3$	76
Table D.4 – Alternative demonstration of arcing times for $k_{pp} = 1,3$	78
Table D.5 – Demonstration of arcing times for $k_{pp} = 1,5$	81
Table D.6 – Alternative demonstration of arcing times for $k_{pp} = 1,5$	83
Table D.7 – Demonstration of arcing times for $k_{pp} = 1,3$	85
Table D.8 – Alternative demonstration of arcing times for $k_{pp} = 1,3$	87
Table D.9 – Procedure for combining $k_{pp} = 1,5$ and 1,3 during test-duties T10, T30, T60 and T100s(b)	89
Table D.10 – Procedure for combining $k_{pp} = 1,5$ and 1,3 during test-duty T100a	90
Table E.1 – Test procedure for $k_{pp} = 1,5$ and 2,5	92
Table E.2 – Test procedure for $k_{pp} = 1,3$ and 2,0	93
Table E.3 – Simplified test procedure for $k_{pp} = 1,3$ and 2,0	94
Table E.4 – Test procedure for $k_{pp} = 1,2$	95
Table E.5 – Simplified test procedure for $k_{pp} = 1,2$	95
Table E.6 – Test procedure for asymmetrical currents for $k_{pp} = 1,5$	96
Table E.7 – Test procedure for asymmetrical currents for $k_{pp} = 1,3$	98
Table E.8 – Test procedure for asymmetrical currents for $k_{pp} = 1,2$	100
Table E.9 – Procedure for combining $k_{pp} = 1,3$ and 1,5 for test-duties T10, T30, T60 and T100s(b)	101
Table E.10 – Procedure for combining $k_{pp} = 2,0$ and 2,5 for test-duties OP1 and OP2(b)	102
Table E.11 – Procedure for combining $k_{pp} = 1,5$ and 1,3 for test-duty T100a	103
Table E.12 – Required test parameters for different asymmetrical conditions in the case of $k_{pp} = 1,5$, $f_r = 50$ Hz	104

Table E.13 – Required test parameters for different asymmetrical conditions in the case of a $k_{pp} = 1,3, f_r = 50$ Hz	106
Table E.14 – Required test parameters for different asymmetrical conditions in the case of $k_{pp} = 1,2, f_r = 50$ Hz	108
Table E.15 – Required test parameters for different asymmetrical conditions in the case of $k_{pp} = 1,5, f_r = 60$ Hz	109
Table E.16 – Required test parameters for different asymmetrical conditions in the case of $k_{pp} = 1,3, f_r = 60$ Hz	111
Table E.17 – Required test parameters for different asymmetrical conditions in the case of $k_{pp} = 1,2, f_r = 60$ Hz	113

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

HIGH-VOLTAGE SWITCHGEAR AND CONTROLGEAR –

Part 101: Synthetic testing

FOREWORD

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This edition includes the following significant technical changes with respect to the second edition:

- a) alignment with the third edition of IEC 62271-100:2021;
- b) update this document with the last methods and techniques used for synthetic tests;